

Zagreb, 23.08. 2016.

Dear Editor,

We would kindly ask you to consider this manuscript:

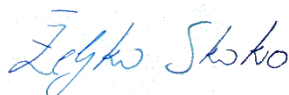
“New algorithm for microstructural information determination from the overlapping X-ray diffraction profiles”

by K. Dekanić, Ž. Skoko and S. Lončarić for publication in the *Acta Chimica Slovenica*.

We hope that the readership of the *Acta Chimica Slovenica* would find the results of our study useful and interesting. Hopefully we have demonstrated that our new method for separation of the overlapping signals, based on the differentiation of the signals, can in many ways improve and accelerate analysis of the X-ray diffraction profiles. Main problem in this analysis occur when the two neighboring profiles overlap. Even though several solutions to this problem are available, most of them are commercial and they demand complex crystallographic knowledge. The method that we propose allows the extraction of microstructural information that are accurate, but even more important, readily available to all the scientist working in the field of the material science, and not strictly crystallographers.

The results described in the manuscript are new and have not been currently considered for publication elsewhere nor have they been published elsewhere in any medium.

Yours sincerely,



Željko Skoko